



# **EMC Test Report**

# **Product Name: Smart Phone**

# Model Number: BKL-L04

# Report No: SYBH(Z-EMC)20171225022001-2

FCC ID: QISBKL-L04

Reliability Laboratory of Huawei Technologies Co., Ltd.

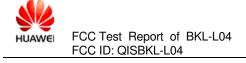
(Global Compliance and Testing Center of Huawei Technologies Co., Ltd)

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# Notice

- 1. The laboratory has obtained the accreditation of China National Accreditation Service for Conformity Assessment (CNAS), and accreditation number: L0310.
- 2. The laboratory has passed the accreditation by The American Association for Laboratory Accreditation (A2LA). The accreditation number is 2174.01
- 3. The laboratory has been listed by Industry Canada to perform electromagnetic emission measurements. The recognition numbers of test site are 6369A-1.
- 4. The laboratory (Reliability Lab of Huawei Technologies Co., Ltd) is also named as "Global Compliance and Testing Center of Huawei Technologies Co., Ltd", the both names have coexisted since 2009.
- 5. The laboratory has been recognized by the US Federal Communications Commission (FCC) to perform compliance testing subject to the Commission's Declaration Of Conformity (DOC) and Certification rules. The Designation Number is CN1173, and the Test Firm Registration Number is 294140."
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- 8. If there is any dissidence for the test report, please file objection to the test centre within 15 days from the date of receiving the test report.
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Applicant:	Huawei Technologies Co., Ltd.		
Address:	Administration Building, Headquarters of Huawei		
	Technologies Co., Ltd., Bantian, Longgang District,		
	Shenzhen, 518129, P.R.C		
Date of Receipt Test Item:	2018-02-02		
Start Date of Test:	2018-02-02		

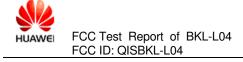
 Start Date of Test:
 2018-02-02

 End Date of Test:
 2018-02-09

**Test Result:** 

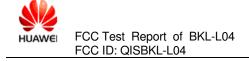
Pass

Approved By	<u>2018-02-12</u>	Roger Zhang	Roger zhang
(Lab Manager)	Date	Name	Signature
Prepared by	2018-02-10	Hua Mei	Hua Mei
(Test Engineer)	Date	Name	Signature



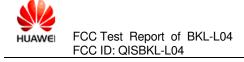
# **Modification Record**

No.	Last Report No.	Modification Description
1	NA	First Report.



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7.2 Conducted Disturbance	7.2	Conducted Disturbance	



# 1 General Information

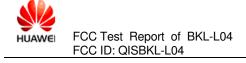
# 1.1 EUT Description

EUT Description			
Product Name	Smart Phone		
Model Number	BKL-L04		
Input voltage	3.8V		
TX Frequency	GSM 850:824MHz to 849MHz PCS 1900:1850MHz to 1910MHz WCDMA Band II: 1850MHz to 1910MHz WCDMA Band IV: 1710MHz to 1755MHz WCDMA Band V: 824MHz to 849MHz LTE BAND 2:1850MHz to 1910MHz LTE BAND 4:1710MHz to 1755MHz LTE BAND 5: 824MHz to 849MHz LTE BAND 5: 824MHz to 849MHz LTE BAND 7:2500MHz to 2570MHz LTE BAND 12:699MHz to 716MHz UTE BAND 17:704MHz to 716MHz WIFI/Bluetooth: 2400MHz to 2483.5MHz 5GWIFI: 5150MHz to 5250MHz 5250MHz to 5350MHz 5470MHz to 5725MHz 5725MHz to 5850MHz NFC: 13.56 MHz		
RX Frequency	GSM 850:869MHz to 894MHz PCS 1900:1930MHz to 1990MHz WCDMA Band II: 1930MHz to 1990MHz WCDMA Band IV: 2110.4MHz to 2155MHz WCDMA Band V: 869MHz to 894MHz LTE BAND 2:1930MHz to 1990MHz LTE BAND 4:2110MHz to 2155MHz LTE BAND 4:2110MHz to 2155MHz LTE BAND 5: 869MHz to 894MHz LTE BAND 5: 869MHz to 894MHz LTE BAND 7:2620MHz to 2690MHz LTE BAND 7:2620MHz to 2690MHz LTE BAND 12:729MHz to 746MHz WIFI/Bluetooth: 2400MHz to 2483.5MHz 5GWIFI: 5150MHz to 5250MHz 5250MHz to 5350MHz 5470MHz to 5725MHz 5725MHz to 5850MHz GPS: 1575.42MHz NFC: 13.56 MHz		
S/N	3SP0118116000014		
HW Version	HL1BKLL04M		
SW Version	BKL-L04 8.1.0.43(C567)		
	EUT Accessory		
Data cable	Data Cable USB A Male to Type C, Shielded Manufacturer: FOXCONN INTERCONNECT TECHNOLOGY LIMITED. LUXSHAREICT MING JI ELECTRONICS.CO.,LTD		



HONGLIN TECHNOLOGY CO.,LTD			
	Manufacturer:Huawei Technologies Co.,Ltd. Model: HW-050450E00 Input voltage: 100-240V 50/60Hz ,0.75A		
	Output voltage: 5V === 2A OR 4.5V === 5A OR		
Adapter	5V <b></b> 4.5A		
	Rated Power: 10W OR 22.5W SN: K92669H9S00075;C82720H9500715; H860K3H9L07783;P83009H4XO4326;		
	Manufacturer:Huawei Technologies Co.,Ltd. Model: HW-050450B00 Input voltage: 100-240V 50/60Hz ,0.75A		
Adapter	Output voltage: 5V === 2A OR 4.5V === 5A OR		
Adapter	5V <b>===</b> 4.5A		
	Rated Power: 10W OR 22.5W SN: K92569H9S00020;C82720H9500080; H830K3H9L07783;P82922H3J31706;		
	Manufacturer:Huawei Technologies Co.,Ltd.		
	Model: HW-050450A00 Input voltage: 100-240V 50/60Hz ,0.75A		
	Output voltage: 5V === 2A OR 4.5V === 5A OR		
Adapter	5V <b>===</b> 4.5A		
	Rated Power: 10W OR 22.5W		
	SN: C82720H9500418; K92469H9S00068; H828K8H3V04673;P82810H5P24582		
	Manufacturer:Huawei Technologies Co.,Ltd.		
	Model: HW-050450U00		
	Input voltage: 100-240V 50/60Hz ,0.75A		
Adapter	Output voltage: 5V === 2A OR 4.5V === 5A OR		
	5V <b>———</b> 4.5A Rated Power: 10W OR 22.5W		
	SN:K92469H9S00068;C82720H9500418; H828K8H5303254; P82810H5P24582;		
	Manufacturer:Huawei Technologies Co.,Ltd.		
	Battery Model: HB386589ECW Rated capacity: 3650mAh		
Rechargeable Li-ion	Nominal Voltage: === +3.82V		
	Charging Voltage: ==== +4.40V		
	SN:2209ACH519;2604SYH110		

Remark: The above EUT's information is declared by manufacturer. Please refer to the specifications or user's manual for more detailed information.



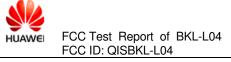
# 1.2 Test Site Information

Test Site 1:	RELIABILITY LABORATORY OF HUAWEI TECHNOLOGIES CO., LTD.
Test Site Location:	Administration Building, Headquarters of Huawei Technologies Co., Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C

# 1.3 Applied Standards

**APPLIED STANDARD** 

# 47 CFR FCC Part 15:2016, Subpart B

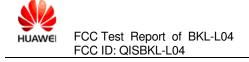


## 2 Summary of Results

Summary of Results						
Test ItemsTest ModePerformance Class & Required Performance CriteriaResult						
Radiated Emissions	Mode 2~	CLASS B	Pass	Site1		
Enclosure Port	Mode 4	ULASS B	r a55	Silei		
Conducted Emissions DC Power Port AC Power Port Telecommunication Ports	Mode 1~ Mode 4	CLASS B	Pass	Site1		
<ul> <li>Note:</li> <li>1, Measurement taken is within the uncertainty of test system.</li> <li>2, ∑ The item has been tested; ☐ The item has not been tested.</li> </ul>						

During the measurement, the environmental conditions complied with the range listed as below.

Item	Required
Ambient temperature	15°C~35°C
Relative humidity	25%~75%
Atmospheric pressure	86kPa~106kPa



## 3 System Configuration during EMC Test

#### 3.1 Test Mode

The EUT was configured, installed, arranged and operated in a manner consistent with typical application. The following mode(s) were applied during the compliance test.

Test Mode	
Mode 1:	Charging +traffic +WIFI+BT+GPS +NFC On +Earphone
Mode 2:	Charging +Camera On +Earphone +idle
Mode 3:	Charging +Video Playing +Earphone +idle
Mode 4:	USB Copy(EUT with PC) +Earphone

Remark:

- If there is one kind of accessories with different models, each one should be applied throughout the compliance test respectively, however, only the worst case will be recorded in this report.
- 2) If EUT has more than one typical operation, only the worst test mode will be recorded in this report.

#### Traffic Mode:

When the EUT state is switched on and with Radio Resource Control (RRC) connection established.

Idle Mode:

When the EUT state is switched on but without Radio Resource Control (RRC) connection.

Worst Case:

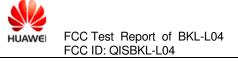
1) Radiated Emission

Model 2: Adapter (HW-050450U00, SN: P82810H5P24582) +Charging +Camera On +Earphone +idle the result is the worst (30MHz~1GHz).

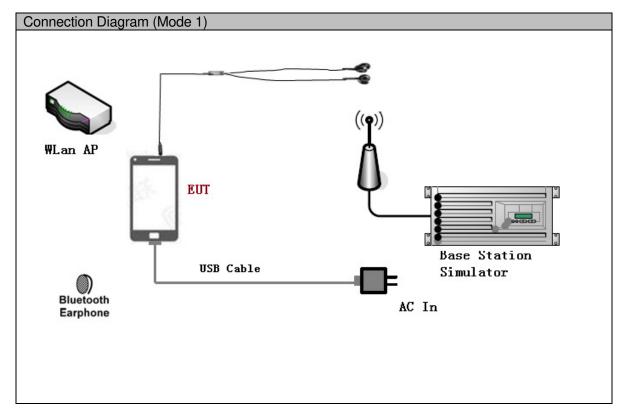
Model 4: USB Copy(EUT with PC) +Earphone the result is the worst (1GHz~18GHz).

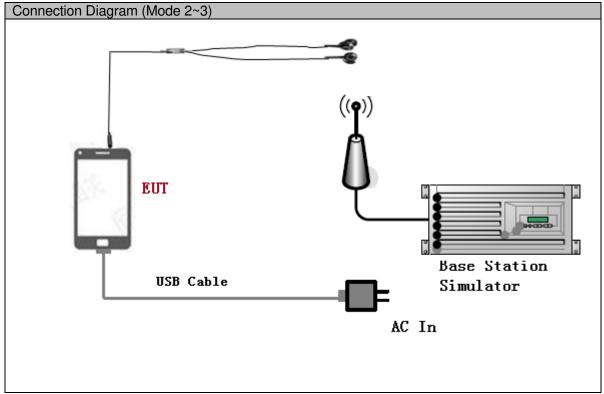
2) Conducted Emission

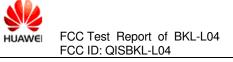
Model 1: Adapter (HW-050450U00, SN: C82720H9500418) + traffic +WIFI+BT+GPS +NFC On +Earphone the result is the worst.

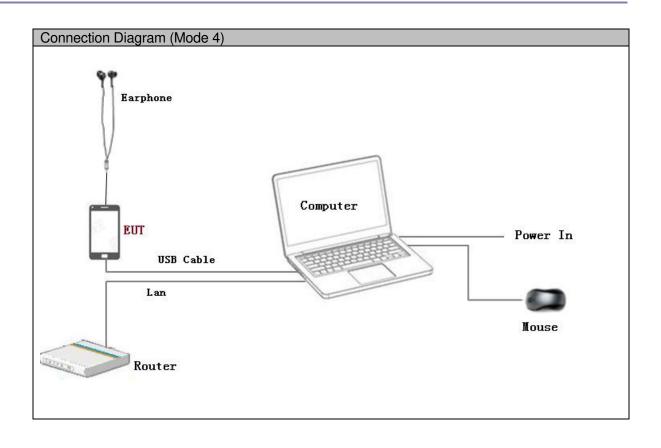


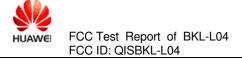
#### 3.2 Test System Configuration









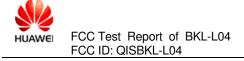


#### 3.3 Cables Used during Test

Cable	Quantity	Length	Type of Cable	
USB	1	<3m	Shielded	

# 3.4 Associated Equipment Used during Test

Name	Model	Manufacturer	S/N	Calibrated Deadline	Cal interval
Radio Communication Tester	CMU200	R&S	3608082535	2018-03-01	12
Radio Communication Tester	MT8820C	Anritsu	A110518805	2018-05-15	12
Notebook	S3	ThinkPad	A140714638	/	/
mouse	M-U0025-O	Lenovo	HS423HB22TB	/	/
Earphone	1311-3291- 3.5mm-229	BOLUO COUNTY QUANCHEN GELECTRON IC CO.,LTD	/	/	/



# 4 Electromagnetic Interference (EMI)

#### 4.1 Radiated Disturbance 30MHz to 40GHz

#### 4.1.1 Test Procedure

The test site semi-anechoic chamber has met the requirement of NSA tolerance 4dB according to the standards: ANCI C63.4: 2014. The test distance was 3m.The set-up and test methods were according to ANCI C63.4: 2014.

A preliminary scan and a final scan of the emissions were made from 30 MHz to 40 GHz by using test script of software; The emissions were measured using Quasi-Peak Detector (30MHz~1GHz) and AV/PK detector (above 1GHz). The maximal emission value was acquired by adjusting the antenna height, polarisation and turntable azimuth in accordance with the software setup. Normally, the height range of antenna was 1m to 4m. The azimuth range of turntable was 0°to 360°. The receiving antenna has two polarizations V and H.

Measurement bandwidth (RBW) for 30MHz to 1000 MHz: 120 kHz;

Measurement bandwidth (RBW) for 1000MHz to 40000 MHz: 1MHz;

EUT was configured in idle mode and the test performed at worst emission state.

# 4.1.2 Test setup

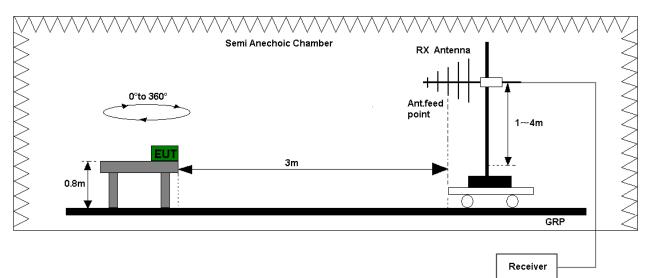
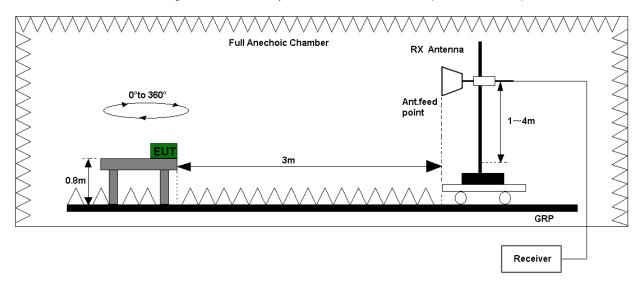
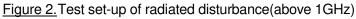
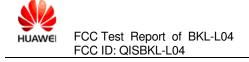


Figure 1. Test set-up of radiated disturbance(30MHz-1GHz )



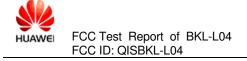




#### 4.1.3 Test Results

The EUT has met the requirements for Radiated Emission of enclosure port. Refer to the section 7.1.1 of this report for test data.

Test Limits (Class B)							
Frequency of Emission (MHz)	Radiated Limit						
(101112)	Unit(µ	V/m)	Unit(dBµV/m)				
30-88	10	0	40				
88-216	15	0	43.5				
216-960	20	0	46				
Above 960	50	0	54				
Above 1000	AV PK		AV	PK			
	500	5000	54	74			



#### 4.2 Conducted Disturbance 0.15 MHz to 30MHz

#### 4.2.1 Test Procedure

The Table-top EUT was placed upon a non-metallic table 0.8 m above the horizontal metal reference ground plane. EUT was connected to LISN and LISN was connected to reference Ground Plane. EUT was 80cm away from LISN. The set-up and test methods were according to ANCI C63.4: 2014 Conducted Disturbance at AC Port measurements were undertaken on the L and N Lines. The emissions were measured using a Quasi-Peak Detector and Average Detector.

EUT was communicated with the simulator through Air interface, the simulator controls the EUT to transmitter the maximum power which defined in specification of product. The EUT operated on the typical channel.

Measurement bandwidth (RBW) for 150 kHz to 30 MHz: 9 kHz;

The EUT was set in the shielded chamber and operated under nominal conditions.

# 4.2.2 Test Setup

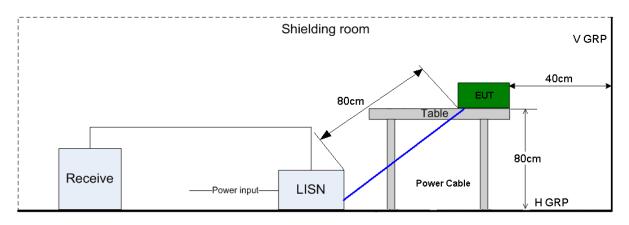
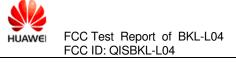


Figure 3. Test Set-up of conducted disturbance

#### 4.2.3 Test Results

The EUT has met requirements for Conducted disturbance of power lines. Refer to the section 7.2.1 of this report for test data.

Test Limit of AC Power Port						
Frequency range	150kHz ~ 30MHz					
Frequency	Voltage limits					
Frequency	QP (dBµV)	AV (dBμV)				
0.15MHz~0.5MHz	66-56	56-46				
0.5MHz-5MHz	56	46				
5MHz~30MHz	60	50				



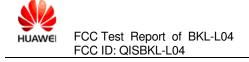
#### 5 <u>Main Test Instruments</u>

Main Test Equipments									
Test item	Ins	Test trument	M	odel	S/N	Manufac er	ctur	Calibrated Deadline	Cal interval
		MI Test eceiver	ES	SU26	100150	R&S		Feb. 20, 2018	12
		oectrum nalyzer	FS	SU43	100048	R&S		Jun. 06, 2018	12
		badband Intenna	VULI	B 9163	9163-491	SCHWA BECł		Mar. 28, 2019	24
RE	Horr	n Antenna	HF	906	100683	R&S		Mar. 28, 2019	24
	-	n antenna to 26.5G) 31		60-09	5140299	ETS		Jul. 20, 2019	24
	-	n antenna .5 to 40G) 3		60-10	00205695	ETS		Jul. 20, 2019	24
	A	mplifier SC		CU26	10021	R&S		May. 16, 2018	12
		EMI Test ES		SU26	100150	R&S		May. 15, 2018	12
CE	-	icial Mains Jetwork		/4200	100134	R&S		May. 15, 2018	12
	-	cial Mains letwork EN		V216	100382	R&S		May. 15, 2018	12
Software Information									
Test Item Software N		lame	Manufacturer			Version			
RE		EMC3	2		R&S			V9.25.0	
CE		EMC3	2		R&S			V9.25.0	

#### 6 System Measurement Uncertainty

For a 95% confidence level, the measurement expanded uncertainties for defined systems, in accordance with the recommendations of ISO 17025 were:

System Measurement Uncertainty						
Items Extended Uncertainty						
RE(30MHz-1GHz)	Field strength (dBµV/m)	U=4.1dB; k=2				
RE(1GHz-18GHz)	U=5.0dB; k=2					
RE(18 GHz-26.5GHz)	Field strength (dBµV/m)	U=4.82dB; k=2				
RE (26.5 GHz- 40GHz)	Field strength (dBµV/m)	U=5.22dB; k=2				
CE	Disturbance Voltage (dBµV)	U=2.5dB; k=2				



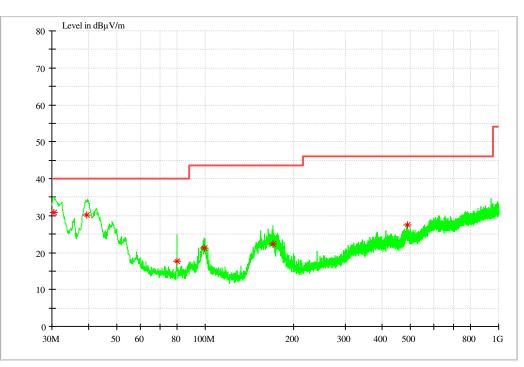
#### 7 Test Data and Graph

Only the worst test results were shown

#### 7.1 Radiated Disturbance

#### 7.1.1 30MHz~1GHz

Test Mode 2: Charging +Camera On +Earphone +idle

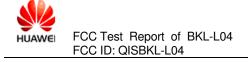


#### MEASUREMENT RESULT: QP Detector

Frequency	Level	Transd	Limit	Margin	Height	Azimuth	
MHz	dBµV/m	dB	dBµV/m	dB	cm	deg	Polarisation
30.472111	30.82	13.8	40	9.18	100	153	V
39.50895	30.27	15.1	40	9.73	100	288	V
79.96595	17.64	10.7	40	22.36	186	34	Н
99.10235	21.12	13.6	43.5	22.38	117	22	V
169.7245	22.43	11.1	43.5	21.07	100	289	V
487.73	27.48	19.9	46	18.52	107	20	Н

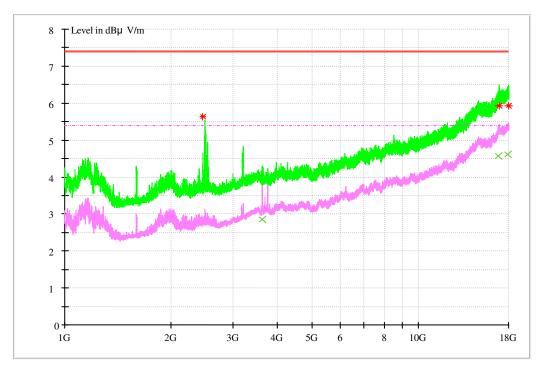
Note:

Level =Reading level by receiver + Transd (Antenna factor + cable loss – preamplifier gain) The reading level is calculated by software which is not shown in the sheet.



# 7.1.2 1GHz~18GHz

Test Mode 4: USB Copy(EUT with PC) +Earphone



#### MEASUREMENT RESULT: PK Detector

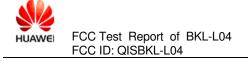
Frequency MHz	Level dBµV/m	Transd dB	Limit dBµV/m	Margin dB	Height cm	Azimuth deg	Polarisation
2509.196667	56.19	-3.6	74	18.81	101	181	Н
16909.83733	59.21	20.9	74	14.79	118	183	V
17984.50933	59.26	21.2	74	14.74	110	13	Н

# MEASUREMENT RESULT: AV Detector

Frequency MHz	Level dBµV/m	Transd dB	Limit dBµV/m	Margin dB	Height cm	Azimuth deg	Polarisation
3612.838	28.6	-3.6	54	25.4	109	140	Н
16865.198	45.72	20.9	54	8.28	100	30	Н
17942.3713	3 46.06	21.5	54	7.94	100	1	Н

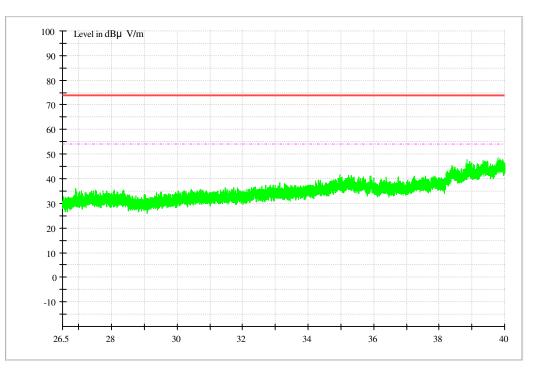
Note:

Level =Reading level by receiver + Transd (Antenna factor + cable loss – preamplifier gain) The reading level is calculated by software which is not shown in the sheet.



# 7.1.3 18GHz~26.5GHz

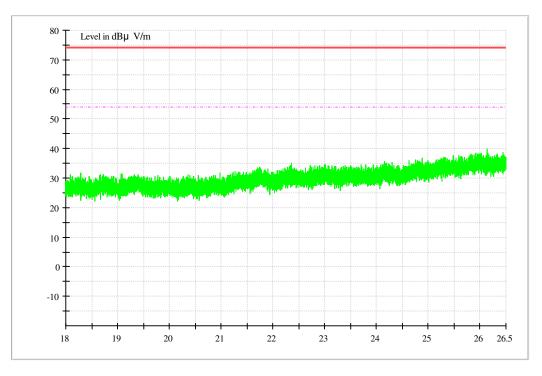
Test Mode 2:Charging +Camera On +Earphone +idle

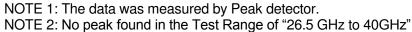


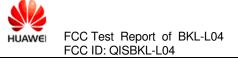
NOTE 1: The data was measured by Peak detector. NOTE 2: No peak found in the Test Range of "18 GHz to 26.5GHz"

# 7.1.4 26.5GHz~40GHz

Test Mode 2:Charging +Camera On +Earphone +idle

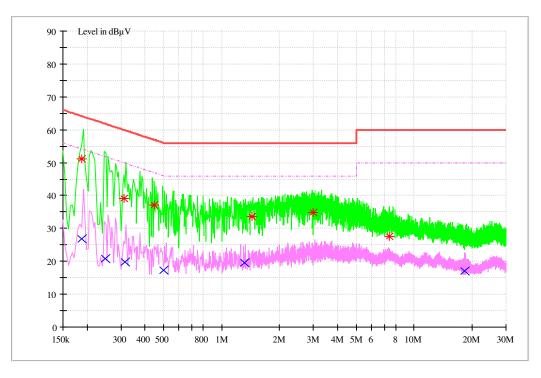






# 7.2 Conducted Disturbance

# 7.2.1 AC Port Test Data



Test Mode 1: Charging +traffic +WIFI+BT+GPS +NFC On +Earphone

#### MEASUREMENT RESULT: QP Detector

Frequency	Level	Line	Transd	Margin	Limit	PE
MHz	dBµV	Line	dB	dB	dBµV	PE
0.18829	51.26	L1	9.7	12.86	64.12	FLO
0.310157	39.09	L1	9.7	20.88	59.97	FLO
0.445251	37.19	L1	9.7	19.77	56.96	FLO
1.446826	33.69	L1	9.7	22.31	56	FLO
2.977542	34.83	L1	9.8	21.17	56	FLO
7.404529	27.7	L1	9.9	32.3	60	FLO

# MEASUREMENT RESULT: AV Detector

Frequency	Level	Line	Transd	Margin	Limit	PE
MHz	dBµV	Line	dB	dB	dBµV	PE
0.186879	26.72	L1	9.7	27.45	54.17	FLO
0.247588	20.82	L1	9.7	31.01	51.83	FLO
0.31497	19.87	L1	9.7	29.97	49.84	FLO
0.49845	17.37	L1	9.7	28.66	46.03	FLO
1.320766	19.55	L1	9.7	26.45	46	FLO
18.380219	17.01	N	10.1	32.99	50	FLO